


<b>Search Notes</b>  	<b>Application/Control No.</b>  10552010	<b>Applicant(s)/Patent Under Reexamination</b>  KASAI ET AL.
	<b>Examiner</b>  Jeffrey Lenihan	<b>Art Unit</b>  4171

SEARCHED			
Class	Subclass	Date	Examiner
525	100, 105, 191, 192	7/30/2008	/JL/

SEARCH NOTES		
Search Notes	Date	Examiner
Performed Inventor Search in eDAN/PALM	7/21/2008	/JL/
Consulted with Walter Choi	7/23/2008	/JL/
NPL Search	7/23/2008	/JL/
See Attached EAST Search History	7/23/2008	/JL/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner